

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/066,828	SUN MICROSYSTEM, INC	
Examiner		Art Unit		Page 1 of 1
Prenell P. Jones		2616		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,205,119	03-2001	Kaczynski, Tomasz	370/231
*	B	US-2001/0034782	10-2001	Kinkade, Ian	709/219
*	C	US-2002/0114305	08-2002	Oyama et al.	370/338
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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